REMARKS

The claims of the present application have been amended in response to the Examiner's Office Action to place the application in condition for allowance. Applicant has made a concerted effort to present claims which clearly define over the prior art of record, and thus to place this case in condition for allowance.

In the Office Action, the Examiner rejected claims 15-26 under 35 U.S.C. § 103(a) as being unpatentable over United States Patent No. 5,841,709 (McClure) in view of United States Patent No. 6,999,357 (Tanishima).

In rejecting the claims, the Examiner pointed out that McClure does not disclose adding access to additional redundant memory which is not required for the repair, and after re-testing the functional memory and adding access to additional redundant memory, testing the additional redundant memory, but asserts that this is disclosed by Tanishima and that it would have been obvious to modify McClure, using Tanishima, to arrive at the present invention.

Independent claim 15 now specifically claims that the step of adding access to additional redundant memory which is not required for the repair occurs **after repairing the functional memory by adding access to redundant elements and after re-testing the functional memory which has been repaired** and the step of testing the additional redundant memory which has been added which was not required for the repair occurs **after repairing and re-testing the functional memory and adding access to the additional redundant memory which has been added which was not required for the repair.** Claim 21 has been similarly amended but is directed to a mode for testing memory.

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Not only does McClure not disclose or suggest providing this, but Tanishima also does not disclose or suggest providing what is now being claimed in claims 15 and 21. While Tanishima teaches, at col. 6, lines 33-36, "to replace the failed memory cell array with the redundant memory cell array" and to thereafter perform tests, the redundant memory cell array is required for the repair.

At col. 8, lines 5-8, Tanishima teaches the ability "to perform the testing of the redundant cell array during the testing step without actual replacement with the redundant memory cell array." As such, the redundant memory cell array is required for the repair, it just may not be used in the end. In Tanishima, this testing is performed before making the repair. Tanishima does not teach testing adding access to additional redundant memory cell arrays after the functional memory is already repaired and re-tested. In Tanishima, the functional memory is not tested, repaired and re-tested before adding access to additional redundant memory, where the additional redundant memory is not required for the repair.
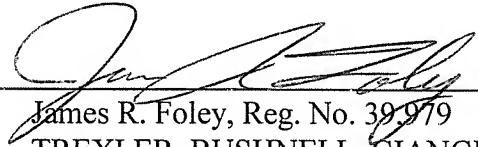
Applicant submits that what is now being claimed in claims 15 and 21 is neither disclosed nor suggested by the cited references, and Applicant respectfully submits that claims 15 and 21, and those claims which depend therefrom, are allowable.

In view of the above amendments and remarks, Applicant respectfully requests that the present application be passed to issuance.

Should the present claims not be deemed adequate to effectively define the patentable subject matter, the Examiner is respectfully urged to call the undersigned attorney of record to discuss the claims in an effort to reach an agreement toward allowance of the present application.

Respectfully submitted,

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